

Contents

137 Dynamic properties and avalanche noise analysis of 4H-SiC over wz-GaN based IMPATTs at mm-wave window frequency

P.R. Tripathy, Moumita Mukherjee, S.P. Pati

145 Optimal solution in producing 32nm CMOS technology transistor with desired leakage current

H.A. Elgomati, I. Ahmad, F. Salehuddin, F.A. Hamid, A. Zaharim, B.Y. Majlis, P.R. Apte

152 Role of Sb additive in the dielectric properties of $\text{Se}_{90}\text{In}_{10}$ and $\text{Se}_{75}\text{In}_{25}$ glassy alloys

J. Sharma, S. Kumar

157 Structural and optical characteristics of ZnSe and CdSe films condensed on non-oriented substrates

M.M. Ivashchenko, A.S. Opanasyuk, N.M. Opanasyuk, S.M. Danilchenko, V.V. Starikov

164 The electric field gradient asymmetry parameter in InSe

Z.D. Kovalyuk, A.G. Khandozhko, G.I. Lastivka, A.P. Samila

167 Photo-thermo-acoustic analysis of heterogeneous semiconductor structures under pulse laser irradiation

R. Burbelo, M. Isaiev, A. Kuzmich

170 Charge transport in bismuth orthogermanate crystals

T.M. Bochkova, S.N. Plyaka

175 Influence of polarization of free-electron system in semiconductor on the position of minimum in plasma light reflection

V.S. Severin

179 Influence of Ca^{2+} ions on the habit of KDP crystals

S. Javidi, R. Enayati, M. Iraj, N. Aliakbari

183 Influence of electron-electron drag on piezoresistance of n -Si

I.I. Boiko

188 Singular analysis of Jones-matrix images describing polycrystalline networks of biological crystals in diagnostics of cholelithiasis in its latent period

V.O. Balanetska, Yu. Marchuk, A.V. Karachevtsev, V.O. Ushenko

195 Probing plasmonic system by the simultaneous measurement of Raman and fluorescence signals of dye molecules

M.M. Dvoynenko, Z.I. Kazantseva, V.V. Strelchuk, O.F. Kolomys, E.G. Bortshagovsky, E.F. Venger, P. Tronc

200 Chemical-dynamic polishing of semiconductor materials based on Bi and Sb chalcogenides by using HNO_3 -HCl solutions

I.I. Pavlovich, Z.F. Tomashik, I.B. Stratiychuk, V.M. Tomashik, O.A. Savchuk, A.S. Kravtsova

203 Impact of sidewall spacer on gate leakage behavior of nano-scale MOSFETs

Ashwani K. Rana, Narottam Chand, Vinod Kapoor

209 Effect of microwave radiation on optical characteristics of thin gold films

P.M. Boltovets

213 The kinetic of point defect transformation during the annealing process in electron – irradiated silicon

G.P. Gaidar, A.P. Dolgolenko, P.G. Litovchenko

222 Information processing in an optoelectronic display system

A.V. Bushma

228 Wavelet analysis of Jones-matrix images corresponding to polycrystalline networks of biological crystals in diagnostics of tuberculosis

N.I. Zabolotna, V.O. Balanetska, O.Yu. Telenga, V.O. Ushenko

237 Photoemission study of the electronic structure of praseodymium filled skutterudite ($\text{PrOs}_4\text{Sb}_{12}$)

J. O. Akinlami, A.M Awobode

241 Electrical properties of MIS structures with silicon nanoclusters

S.V. Bunak, V.V. Ilchenko, V.P. Melnik, I.M. Hatsevych, B.N. Romanyuk, A.G. Shkavro, O.V. Tretyak

247 Structural properties of nanocomposite $\text{SiO}_2(\text{Si})$ films obtained by ion-plasma sputtering and thermal annealing

O.L. Bratus', A.A. Evtukh, O.S. Lytvyn, M.V. Voitovych, V.O. Yukhymchuk

256 Dielectric and electro-optical properties of solutions of chemically modified fullerene C60 in nematic liquid crystal

V.E. Vovk, O.V. Kovalchuk, M.P. Gorishnyj, T.M. Kovalchuk

261 Contents